Hybrid 8j22 Traveler

November 9, 1999

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J22 has die: 052-041 053-001 053-002 053-003 053-039 053-040 053-042 053-043

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j22 classification info. Created 13:20:47 11/05/99

Hybrid 8j22 quality: bad
Chip classification: fair good fair fair bad good fair good
Bad channels (chip-channel): 0-12 4-39 4-48 4-49 4-51 4-52 4-90 4-91 6-20
Bad cells: none
Random bad capacitors (chip-cell-channel): 0-28-12 0-28-13 2-0-103
   3-10-76 4-1-90 4-10-90 4-10-91 4-11-90 4-23-90 4-36-90 4-40-90
   4-41-39 4-43-90 4-45-90 6-8-31
Channels at pedestal needed for DCMS: 35.6 34.6 34.7 34.1 34.6 34.6 34.4 33.6
```

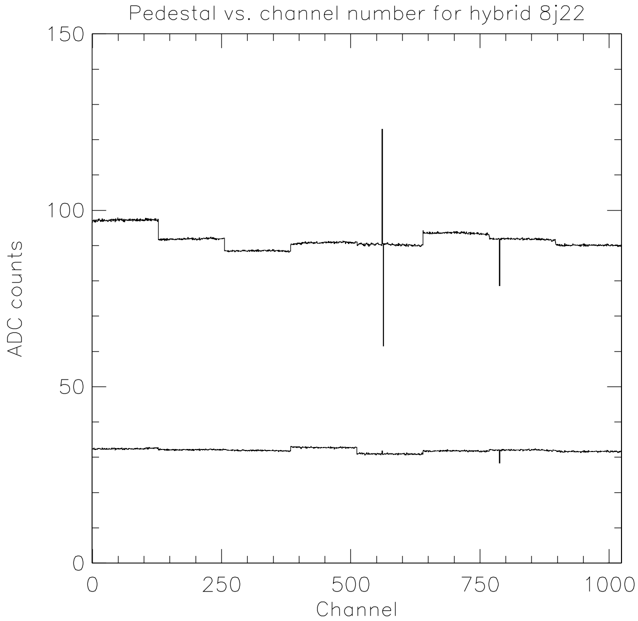
4 Comments

No comments.

5 Pedestal

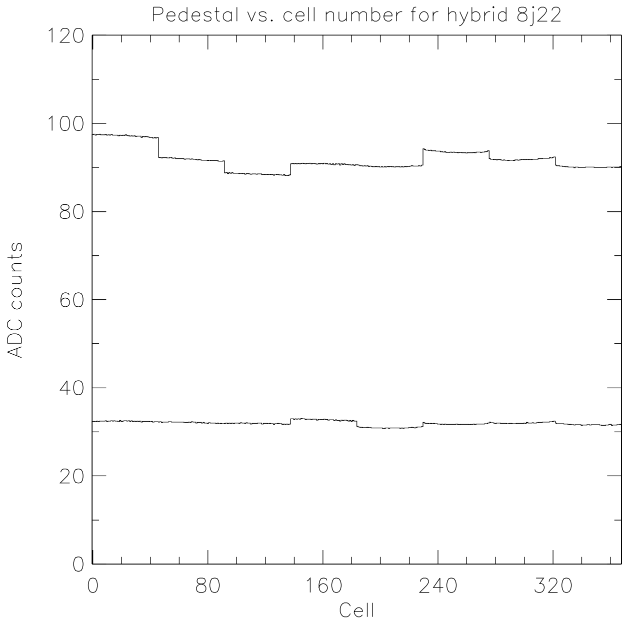
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

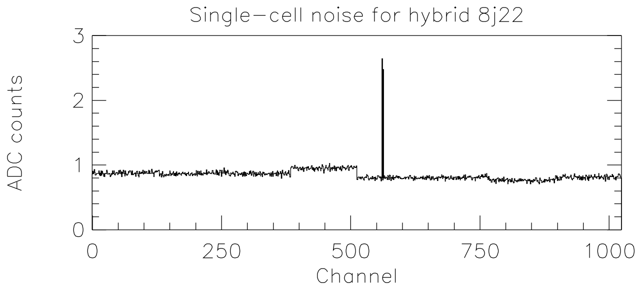
Pedestal vs. Pipeline Cell ID

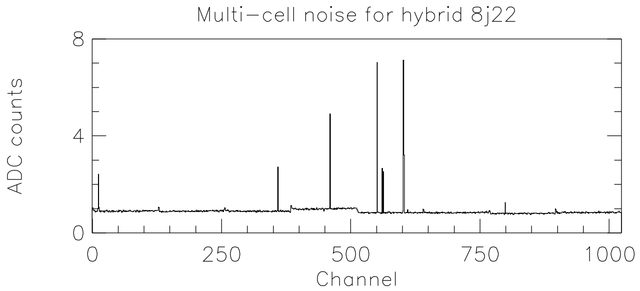


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

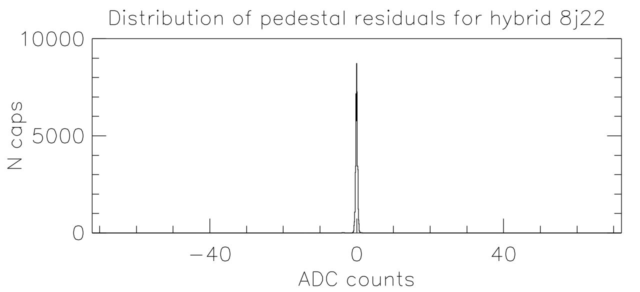
RMS Noise

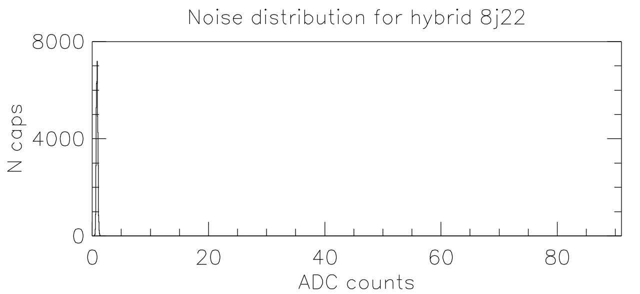




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in